

FIG. 1

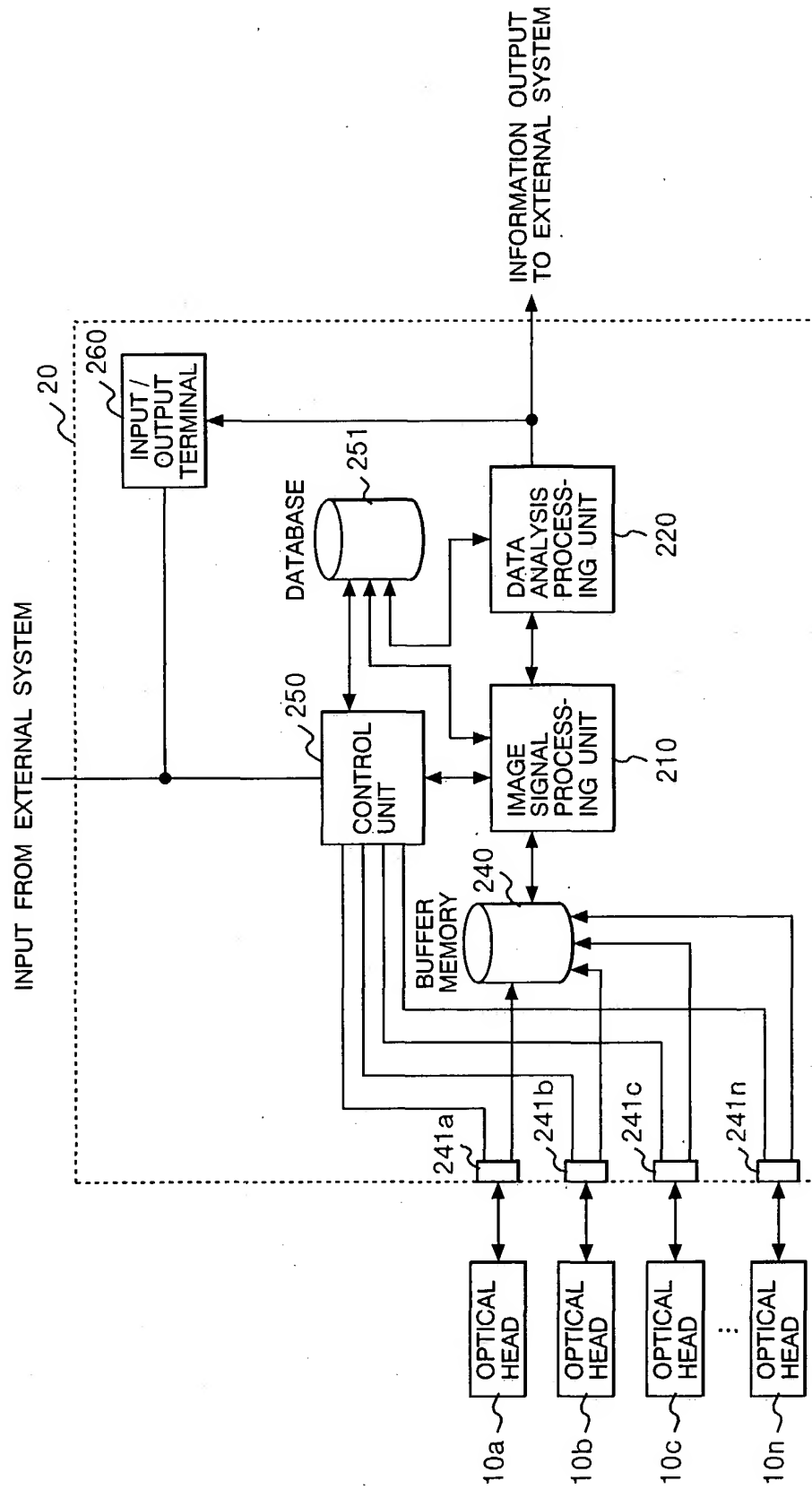


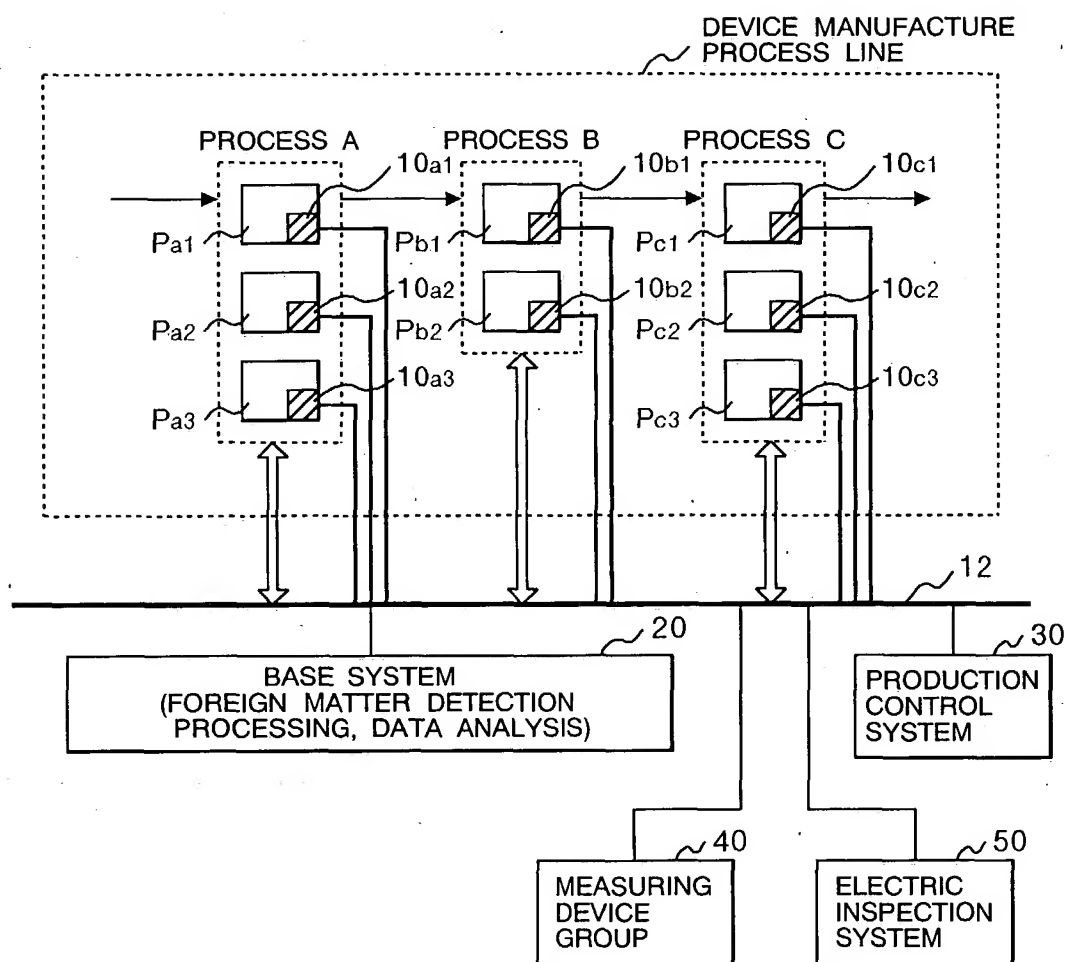
FIG. 2

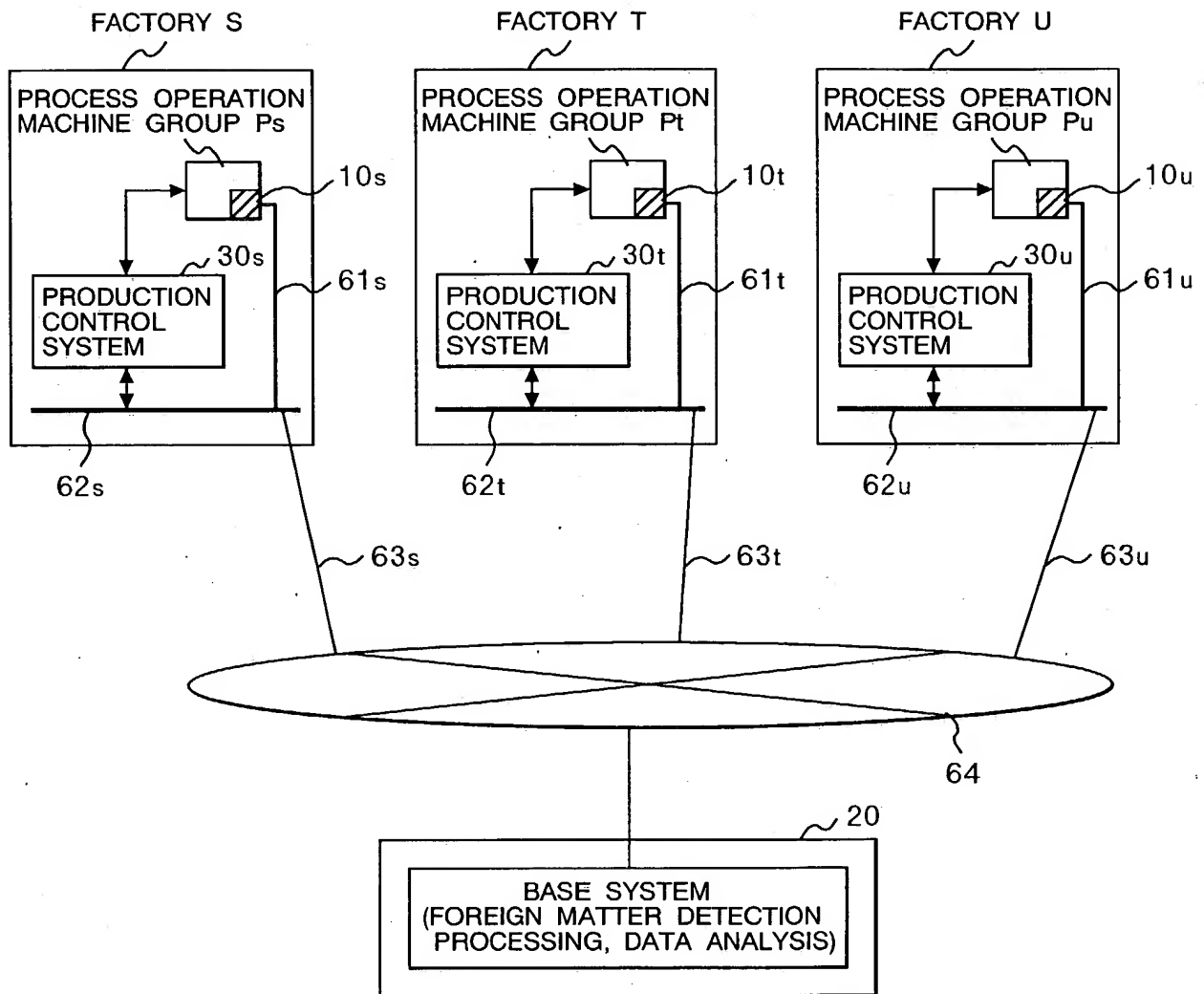
FIG. 3

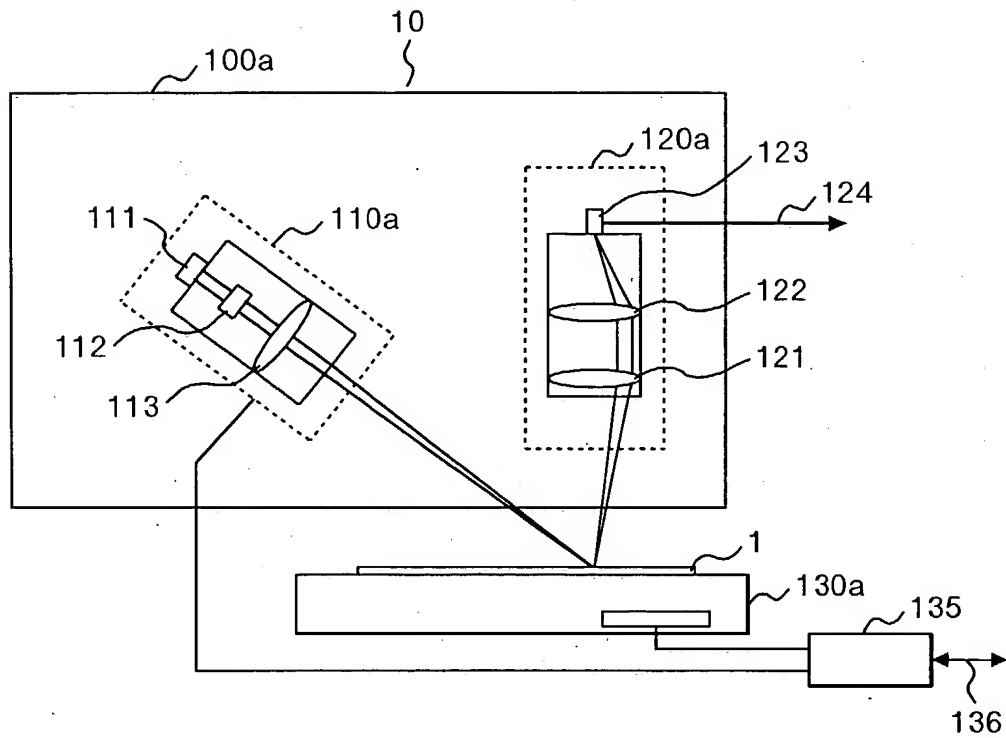
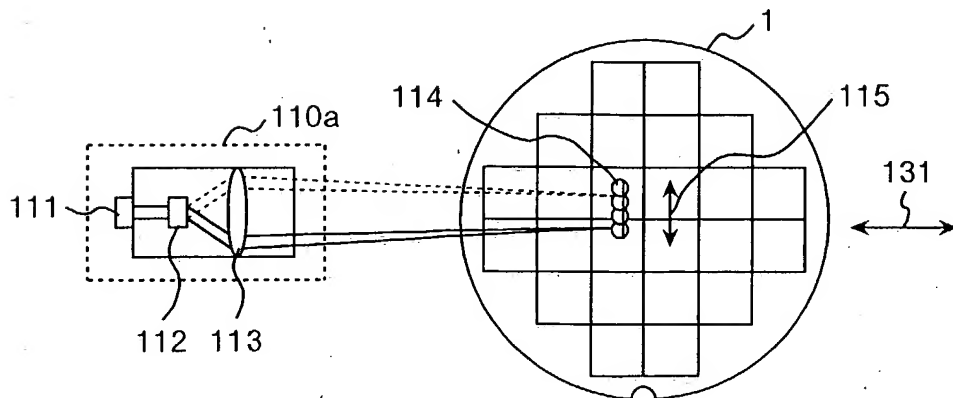
FIG. 4**FIG. 5**

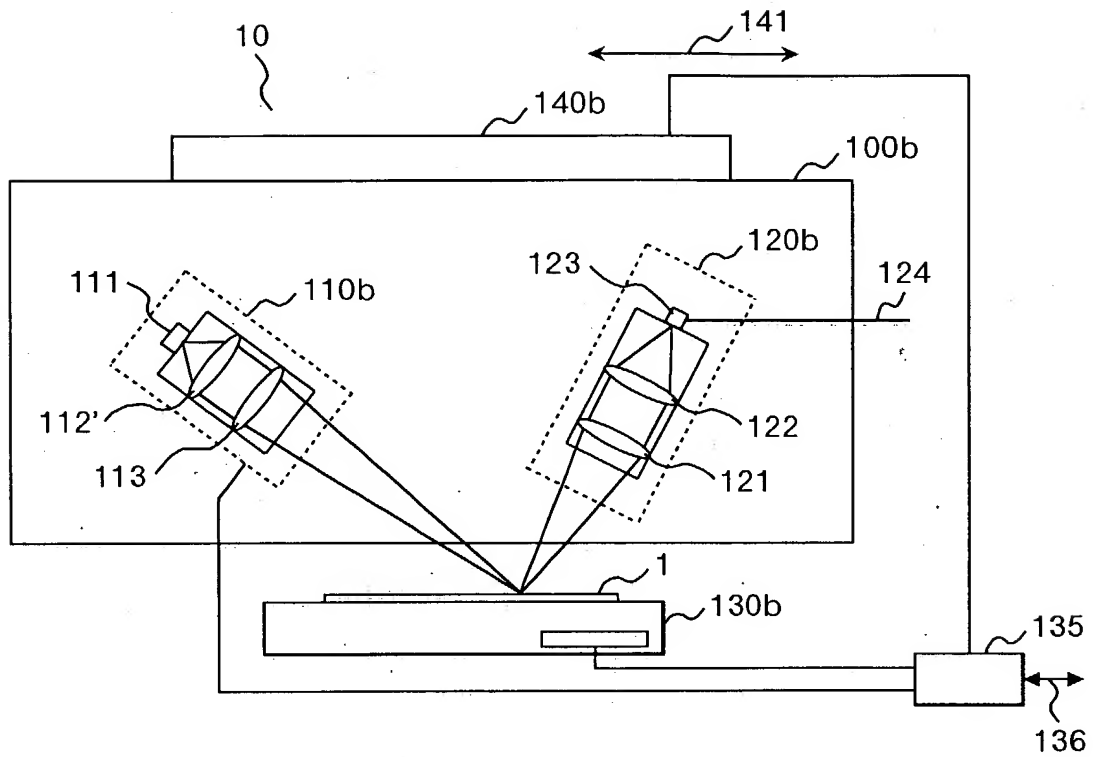
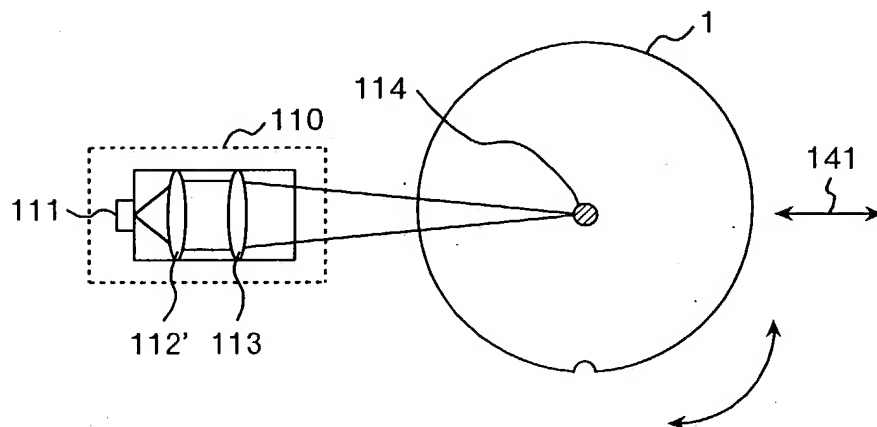
FIG. 6**FIG. 7**

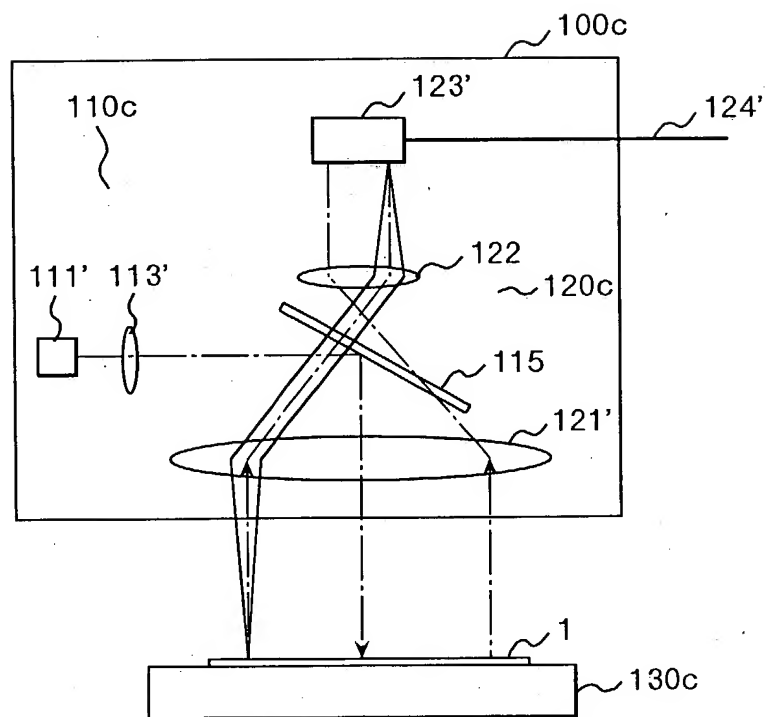
FIG. 8

FIG. 9a

WHOLE WAFER SURFACE INSPECTION

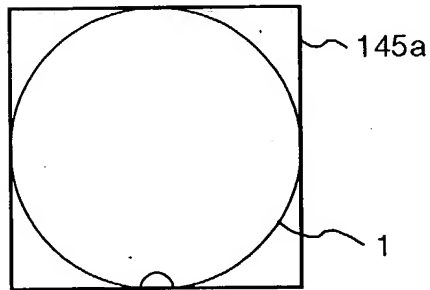


FIG. 9b

PIXEL SIZE REDUCED

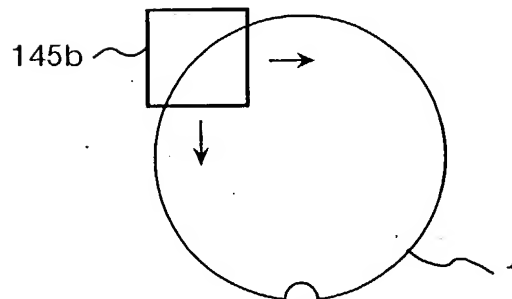


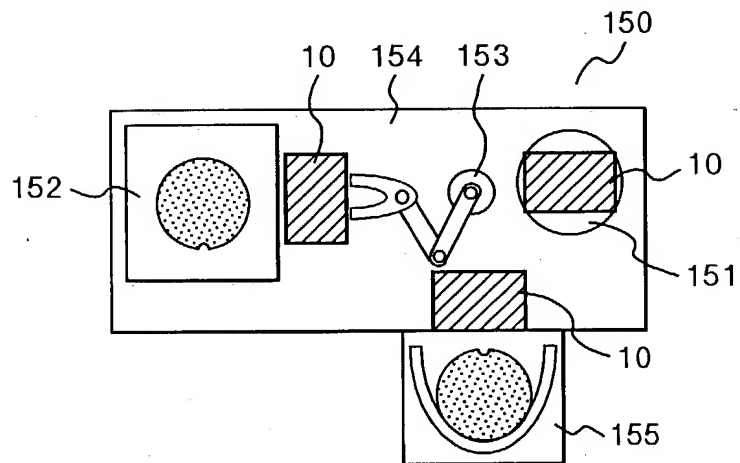
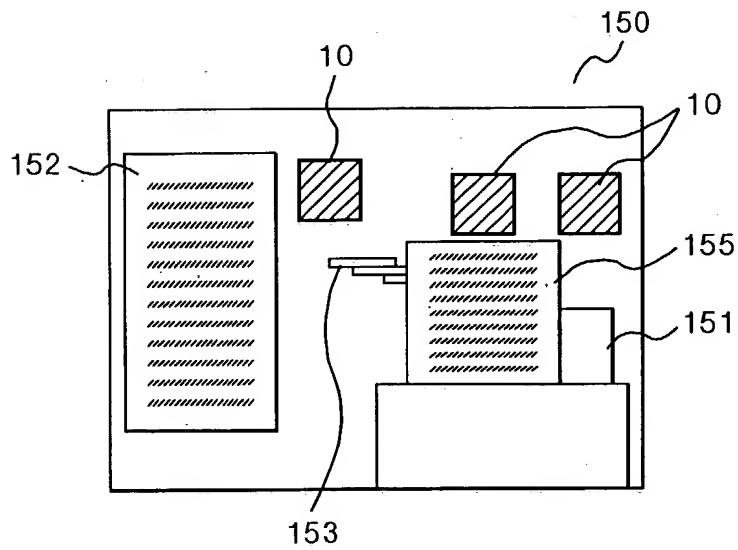
FIG. 10a**FIG. 10b**

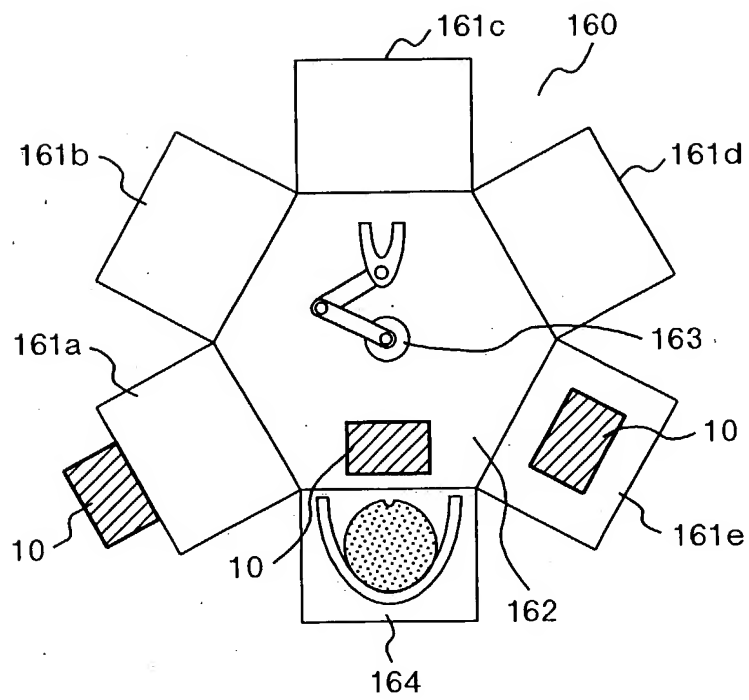
FIG. 11

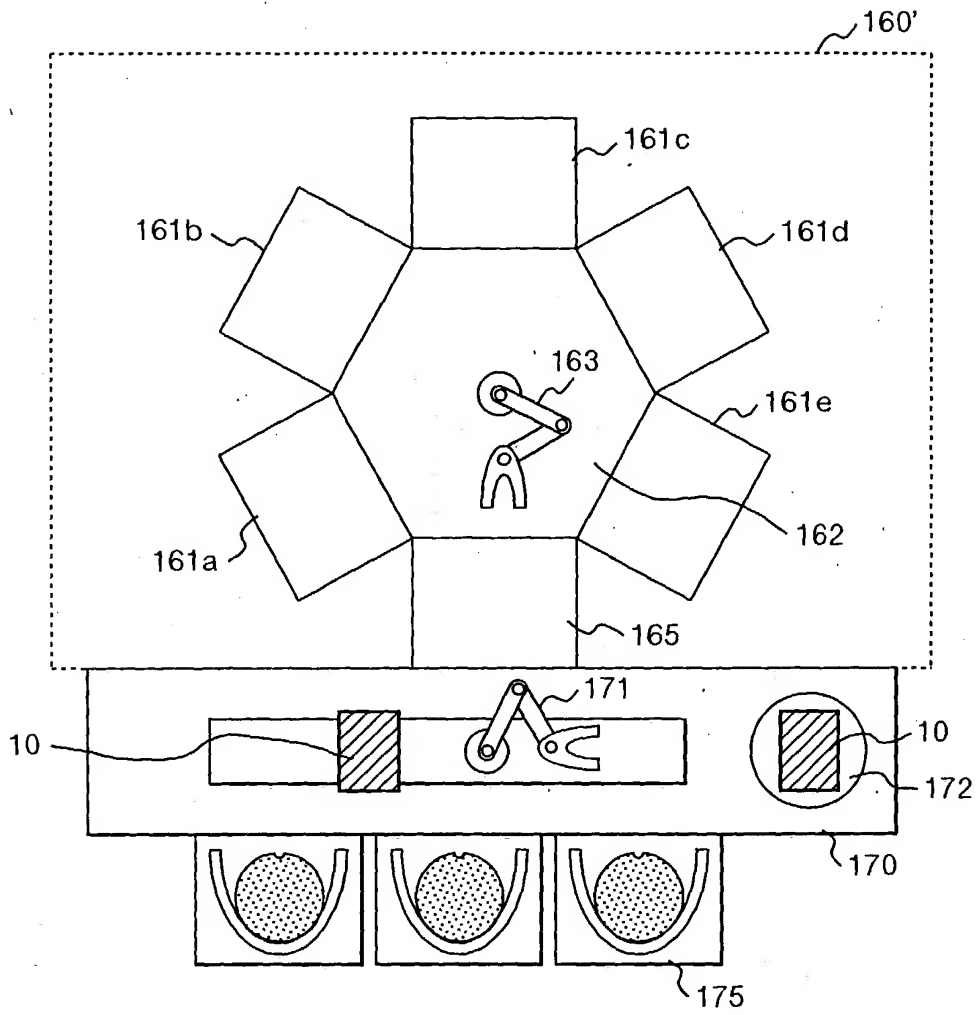
FIG. 12

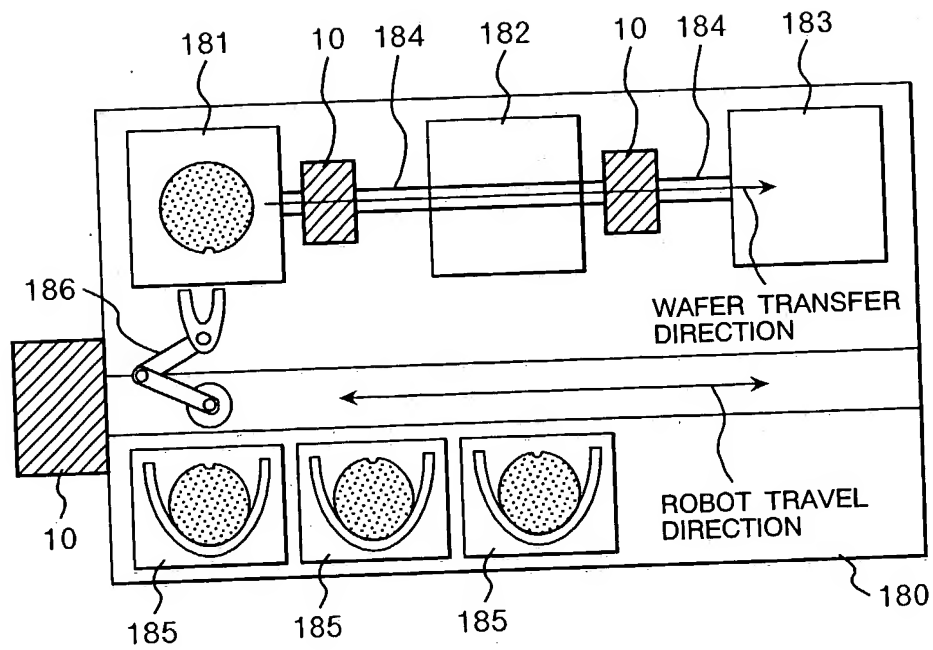
FIG. 13

FIG. 14

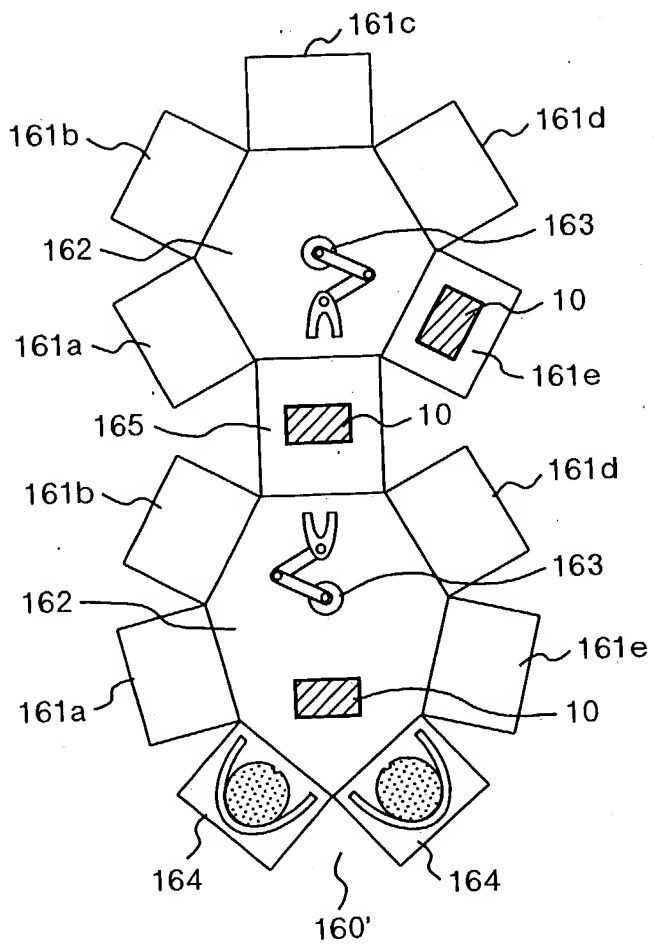


FIG. 15

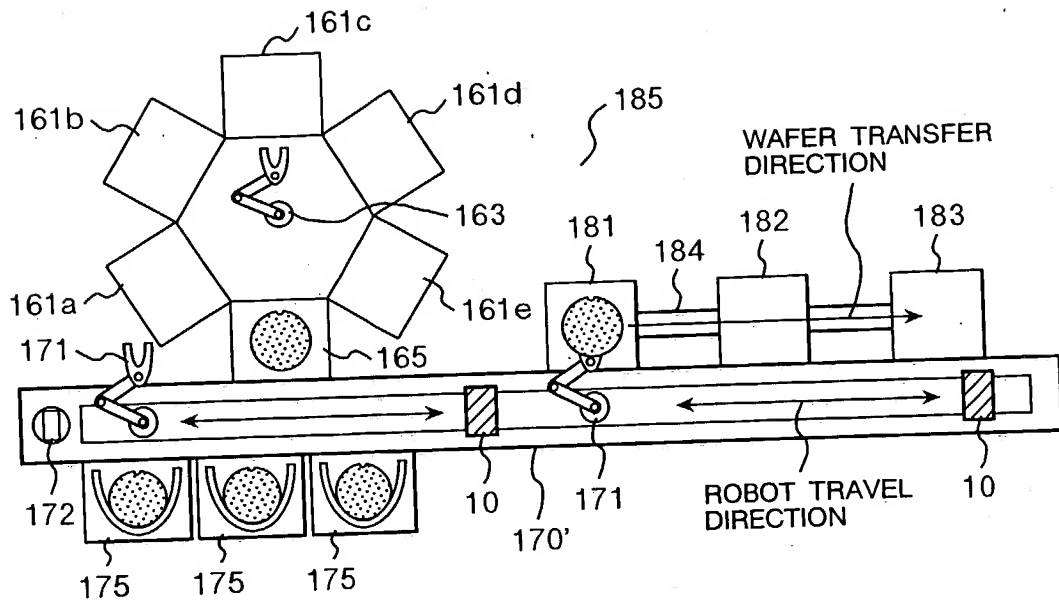


FIG. 16

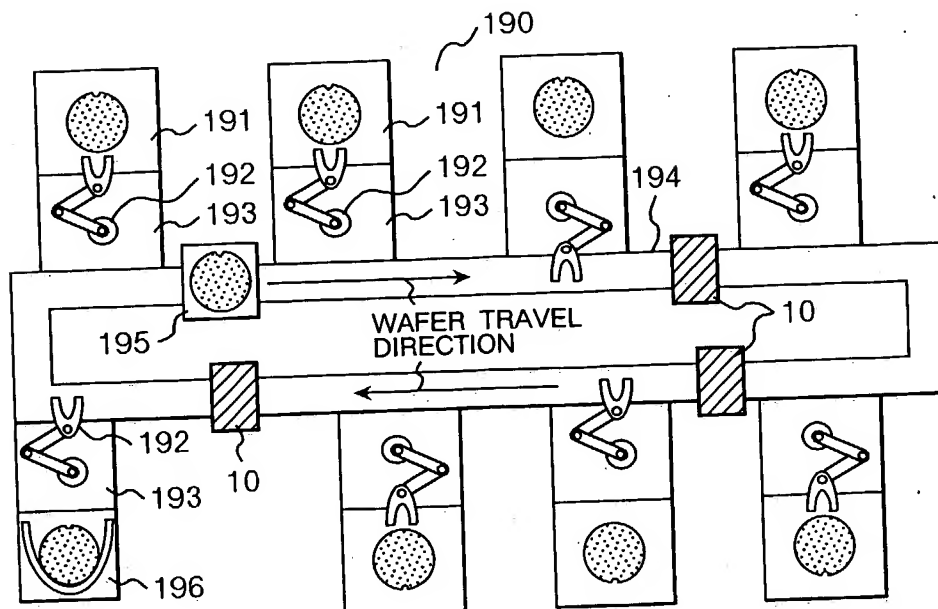


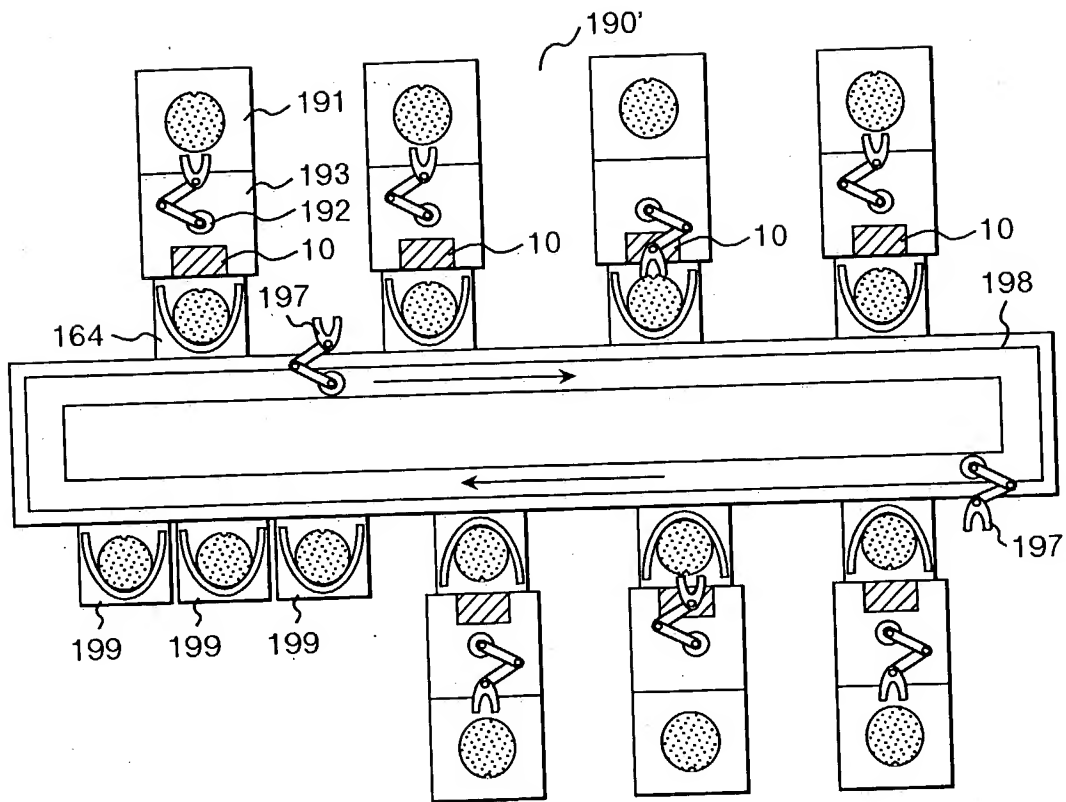
FIG. 17

FIG. 18

- 251
- (a) WAFER PROCESS DATA
 - (b) LAYOUT DATA ON WAFER
 - (c) INSPECTION REQUIREMENTS DATA ON PRODUCTION APPARATUS AND COMPACT FOREIGN MATTER MONITOR
 - (d) INSPECTION REFERENCE IMAGE DATA 216
 - (e) INSPECTION RECIPE DATA
 - ((e-1) THRESHOLD FOR JUDGMENT, (e-2) QUANTITY OF ILLUMINATION LIGHT, (e-3) INSPECTION AREA, (e-4) INSPECTION METHOD (XY SCAN, ROTARY SCAN), ETC.)
 - (f) INSPECTION RESULT DATA
 - (g) DEFECTIVE AREA IMAGE DATA
 - (h) FAILURE ANALYSIS REFERENCE DATA
 - (FOREIGN MATTER DISTRIBUTION DATA)

FIG. 19

- 250
- ① COMPACT FOREIGN MATTER MONITOR (OPTICAL HEAD) ON / OFF MONITOR FUNCTION
 - ② SIGNAL PROCESSING TIMING CONTROL (INPUT / OUTPUT CONTROL) FUNCTION
 - ③ INSPECTION RECIPE PREPARE FUNCTION
 - ④ IDENTIFICATION CODE RECOGNIZE FUNCTION
 - ⑤ INSPECTION RECIPE SELECT FUNCTION
 - ⑥ ALARM OUTPUT FUNCTION
 - ⑦ COMPACT FOREIGN MATTER MONITOR OPTICAL HEAD MAINTENANCE MANAGEMENT FUNCTION
(FOR EXAMPLE, REPLACEMENT MANAGEMENT OF LIGHT SOURCE EVERY n WAFERS INSPECTED)

FIG. 20

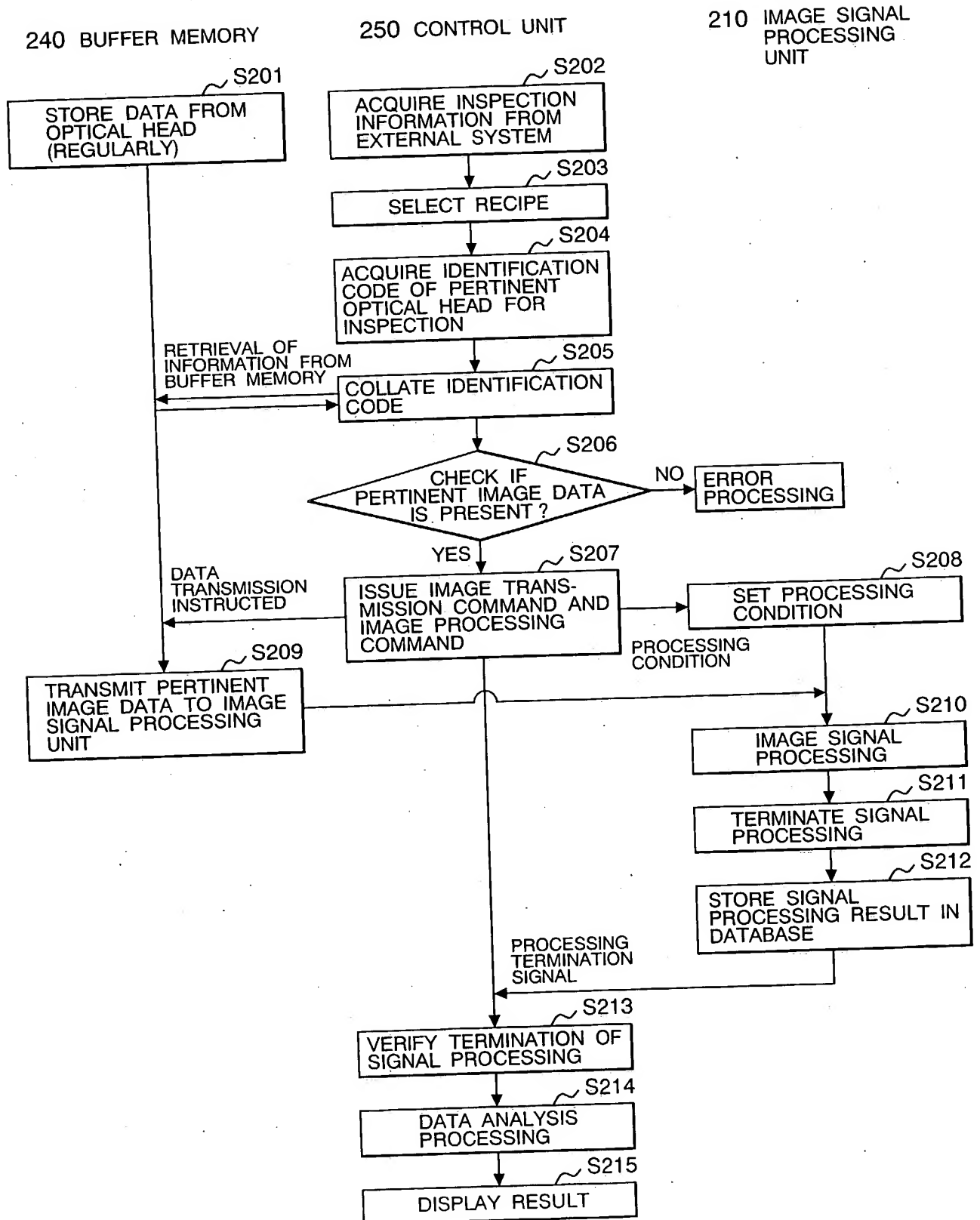


FIG. 21

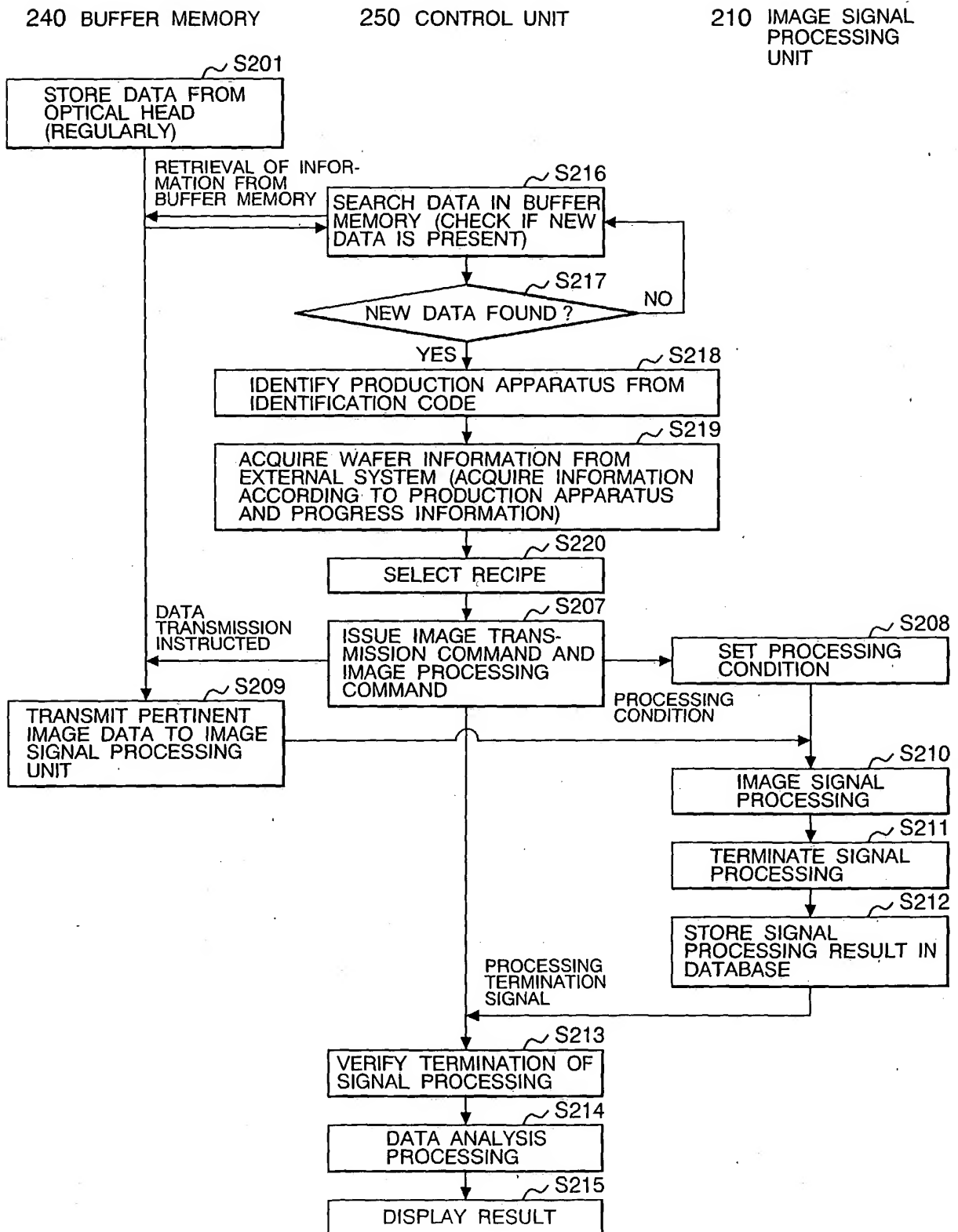


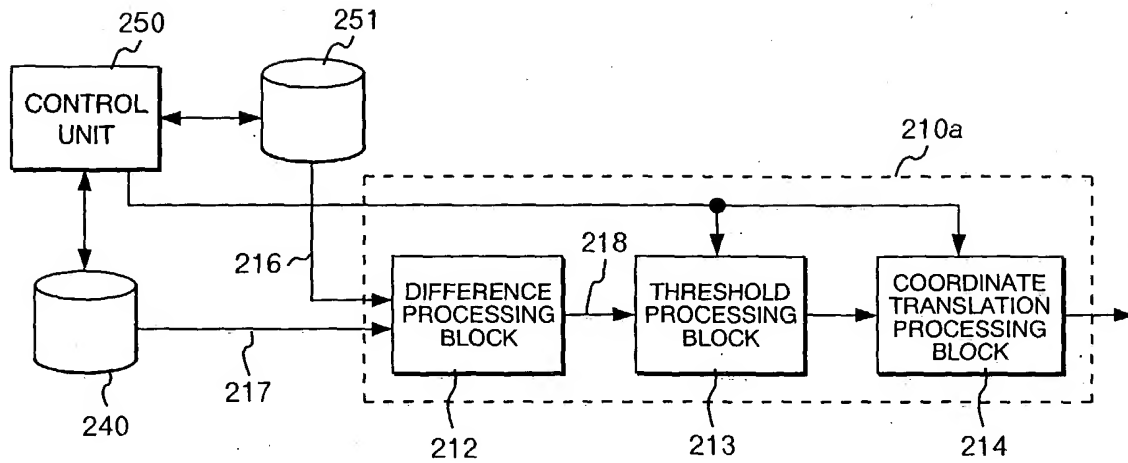
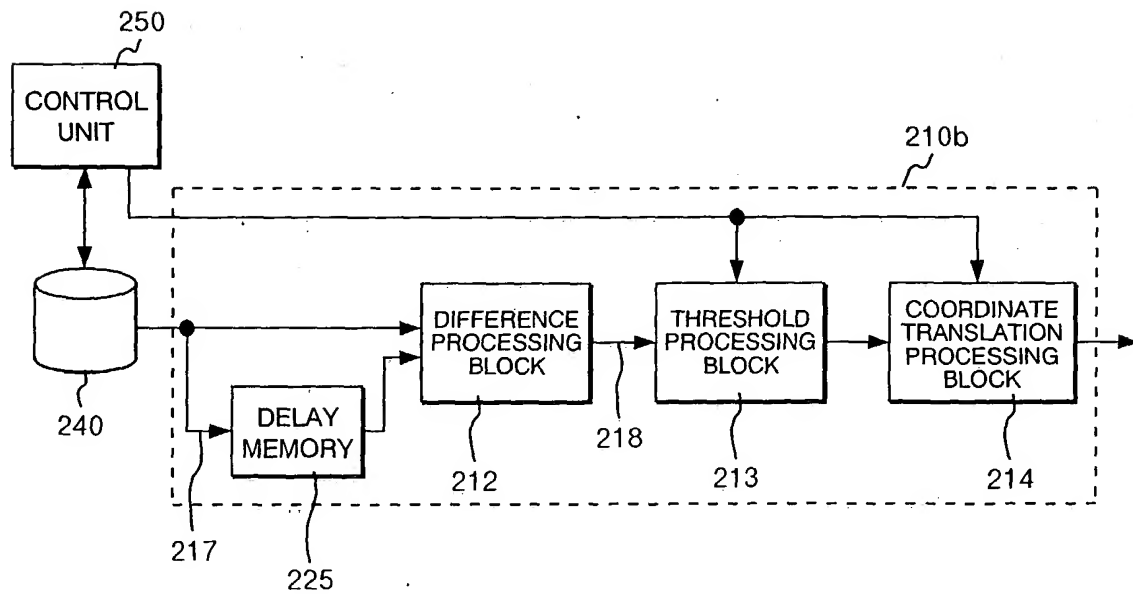
FIG. 22**FIG. 23**

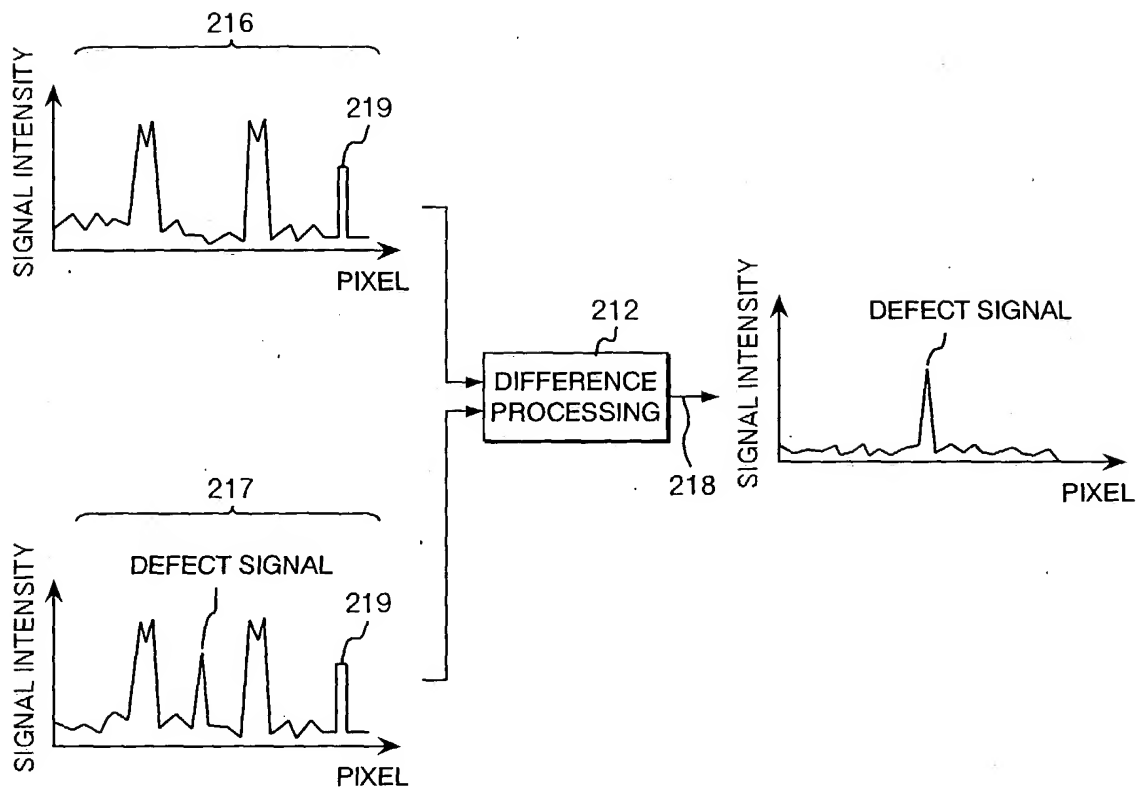
FIG. 24

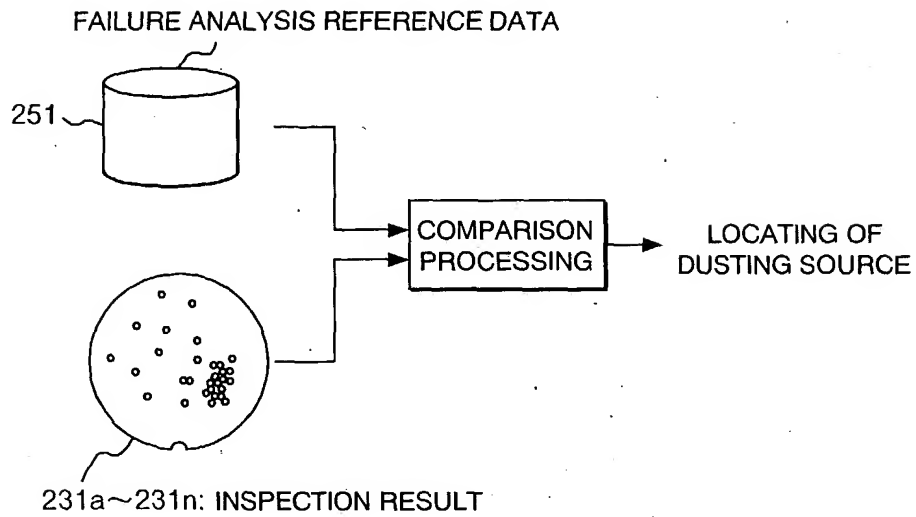
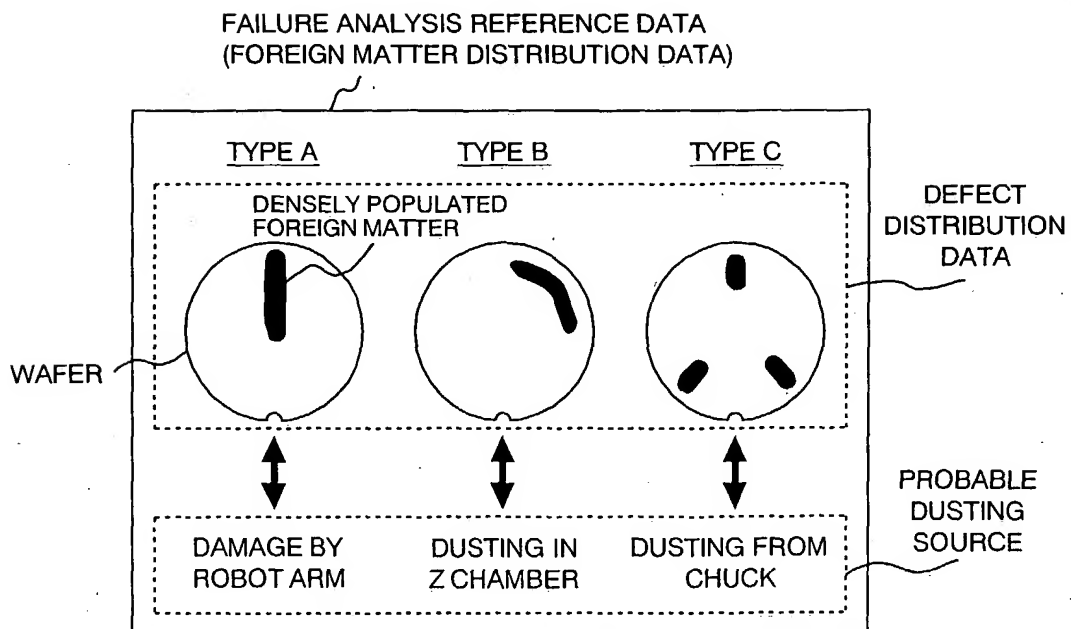
FIG. 25**FIG. 26**

FIG. 27

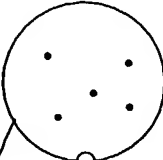
JUDGE BY
INSPECTION RESULT

EQUIPMENT NAME : LOT NO. :

PRODUCT NAME :

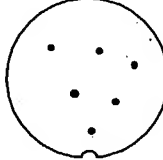
PROCESS NAME :

Status: OCCURRENCE OF
ABNORMALITY
(DAMAGE BY ARM) 271

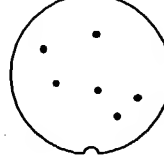


SLOT : 1

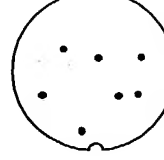
INSPECTION
RESULT



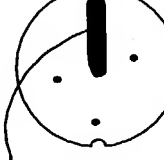
SLOT : 2



SLOT : 3



SLOT : 4



SLOT : 5

INSPECTION RESULT
OF DEFECTIVE WAFER

SLOT : 6

SLOT : 7

SLOT : 8

SLOT : 9

SLOT : 10

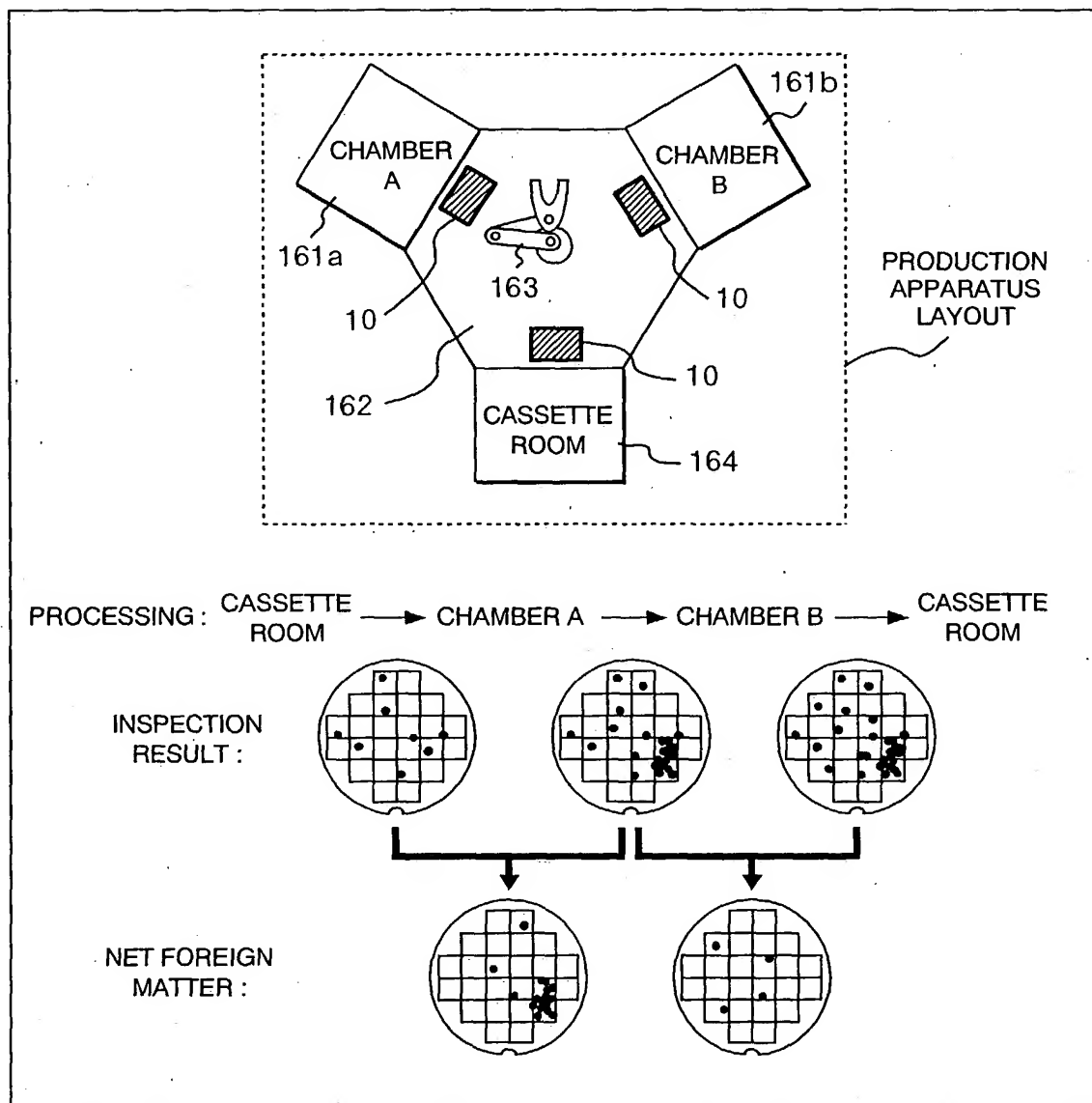
FIG. 28

FIG. 29

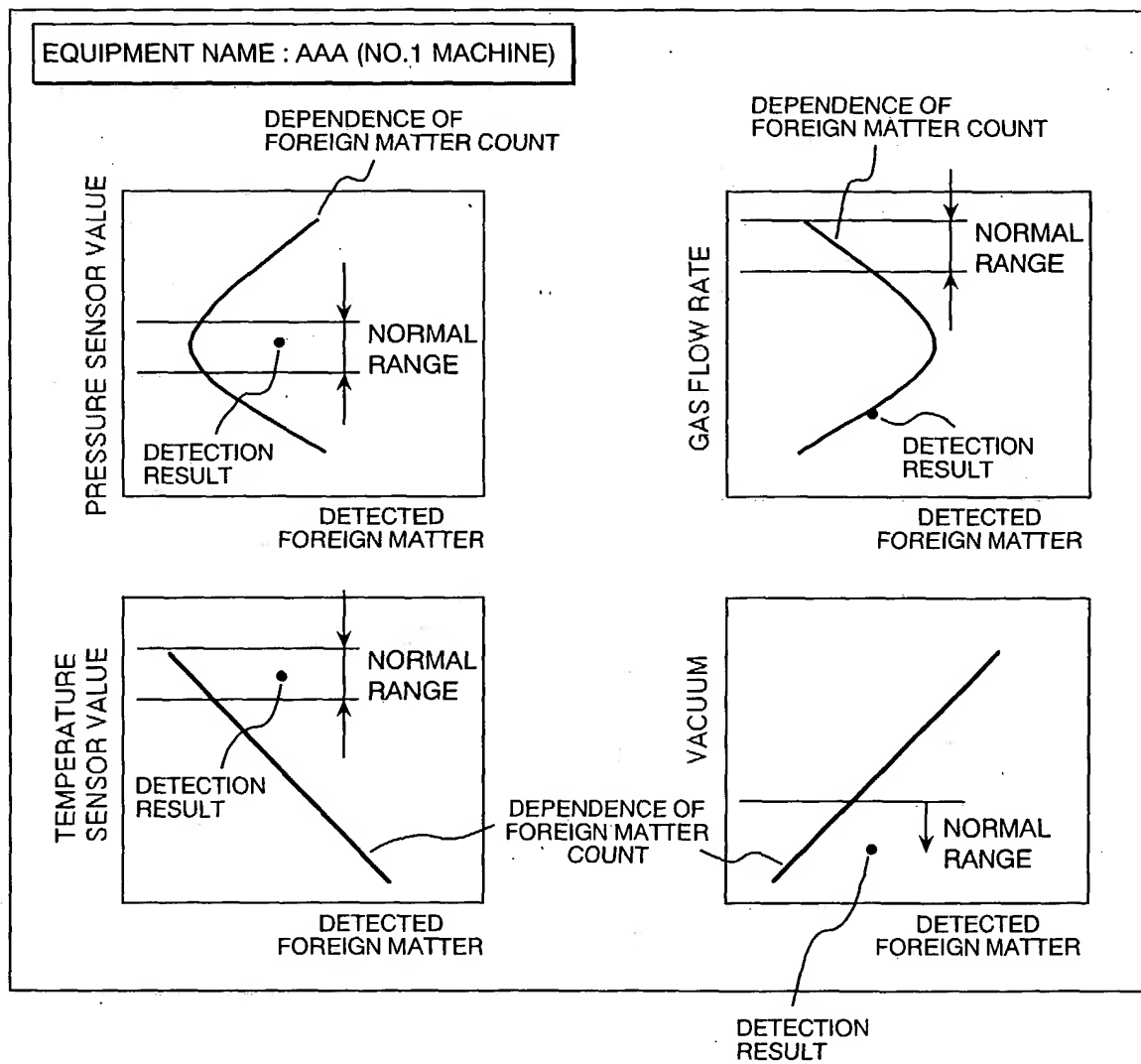


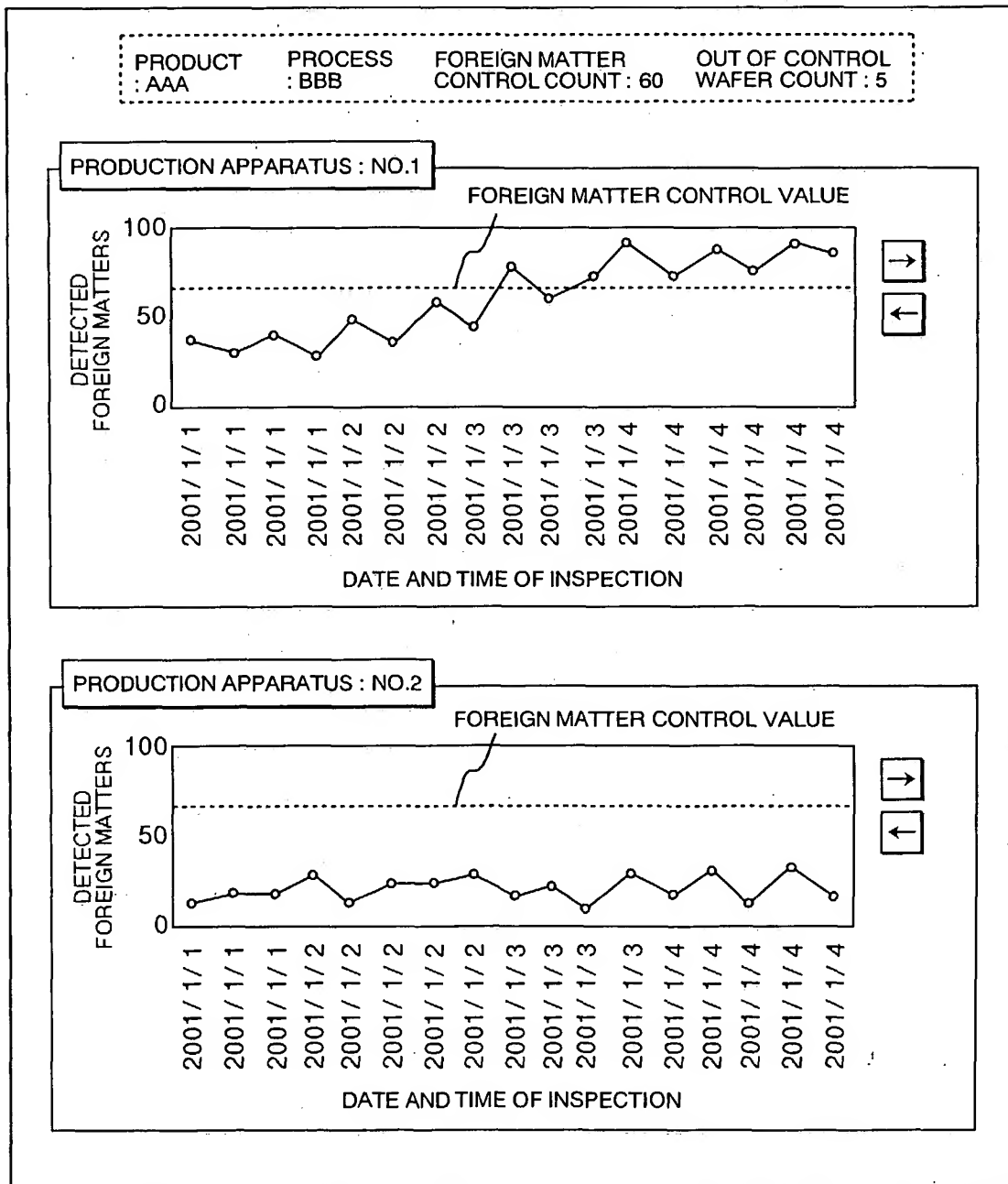
FIG. 30

FIG. 31

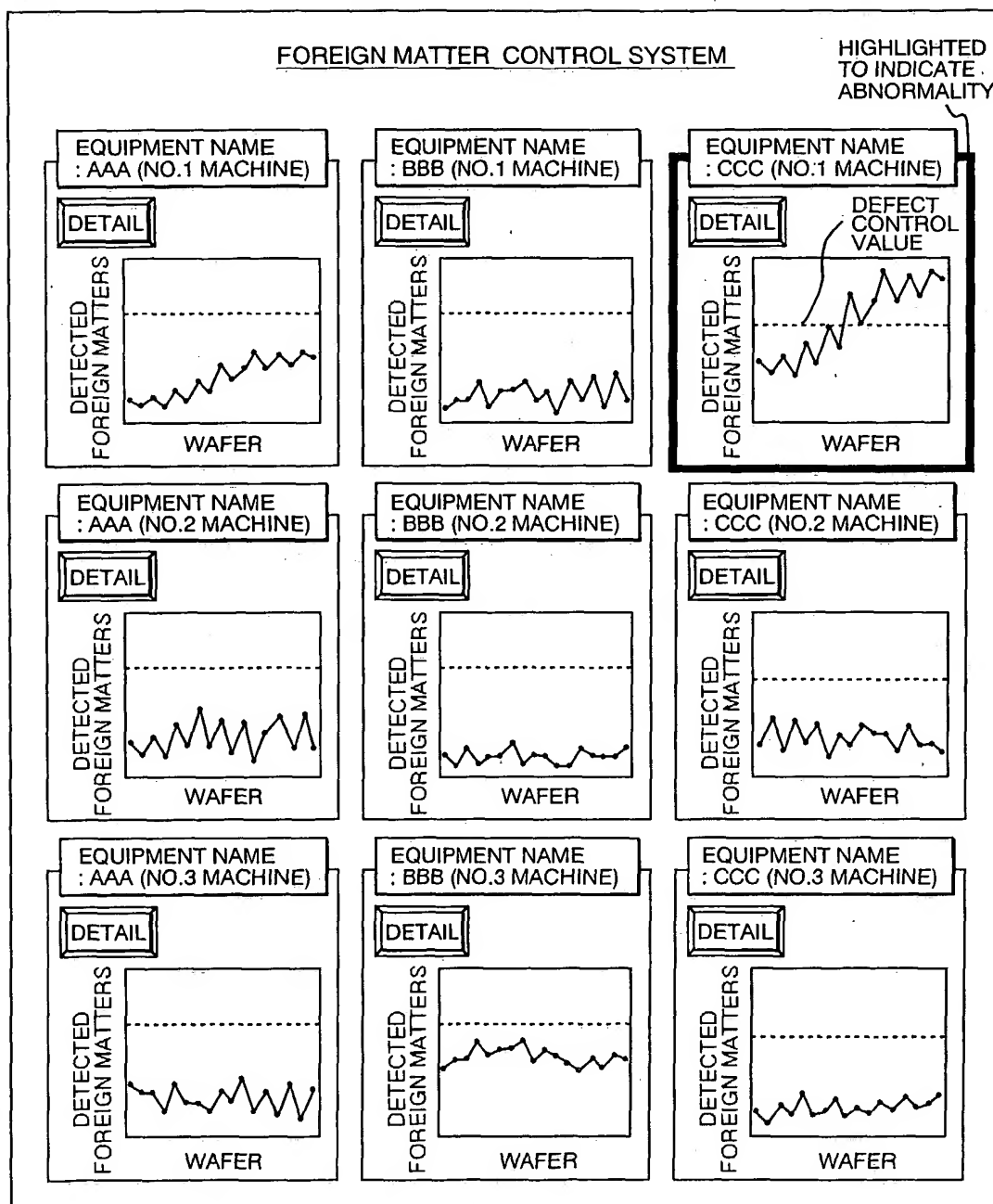


FIG. 32

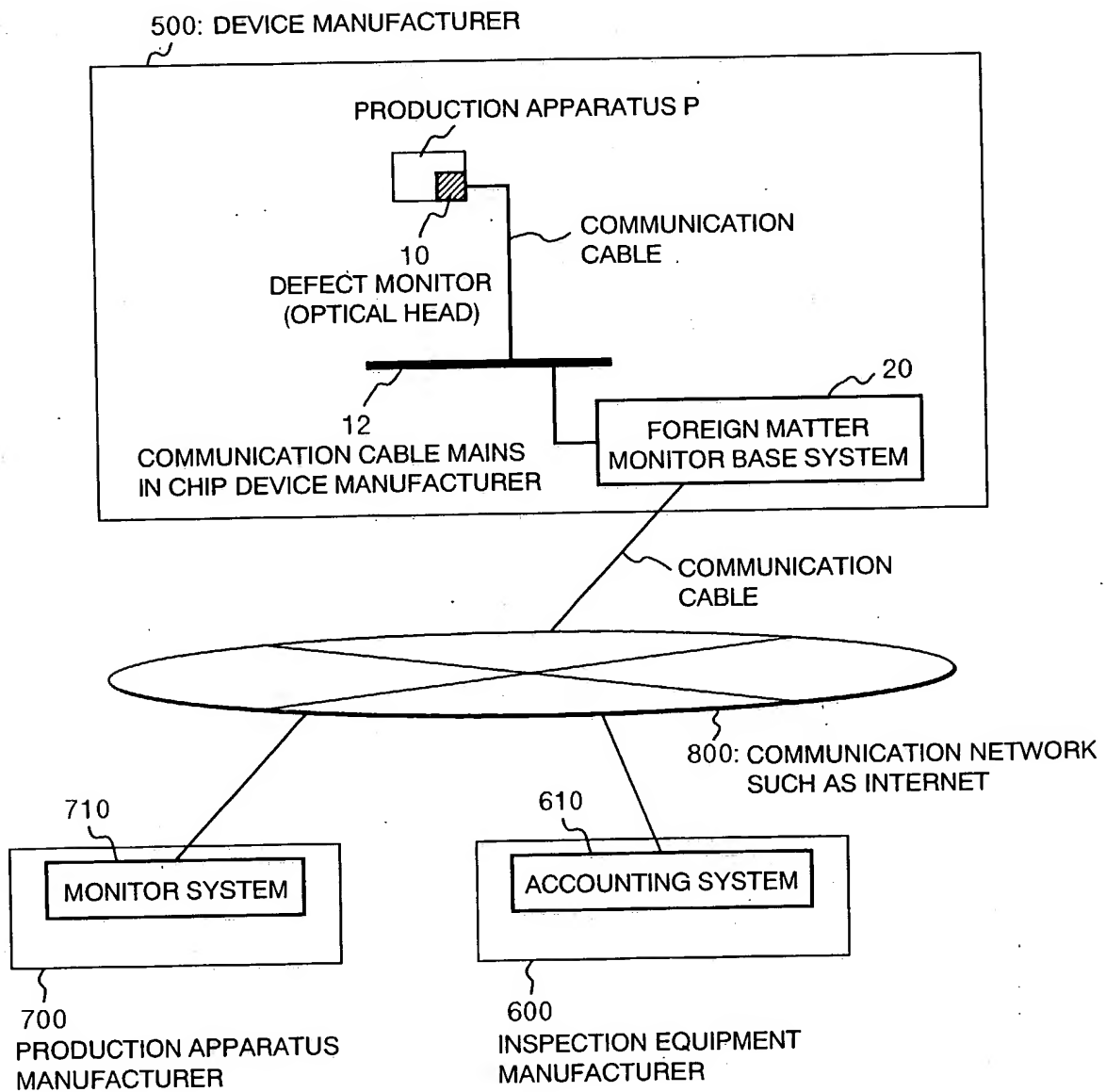


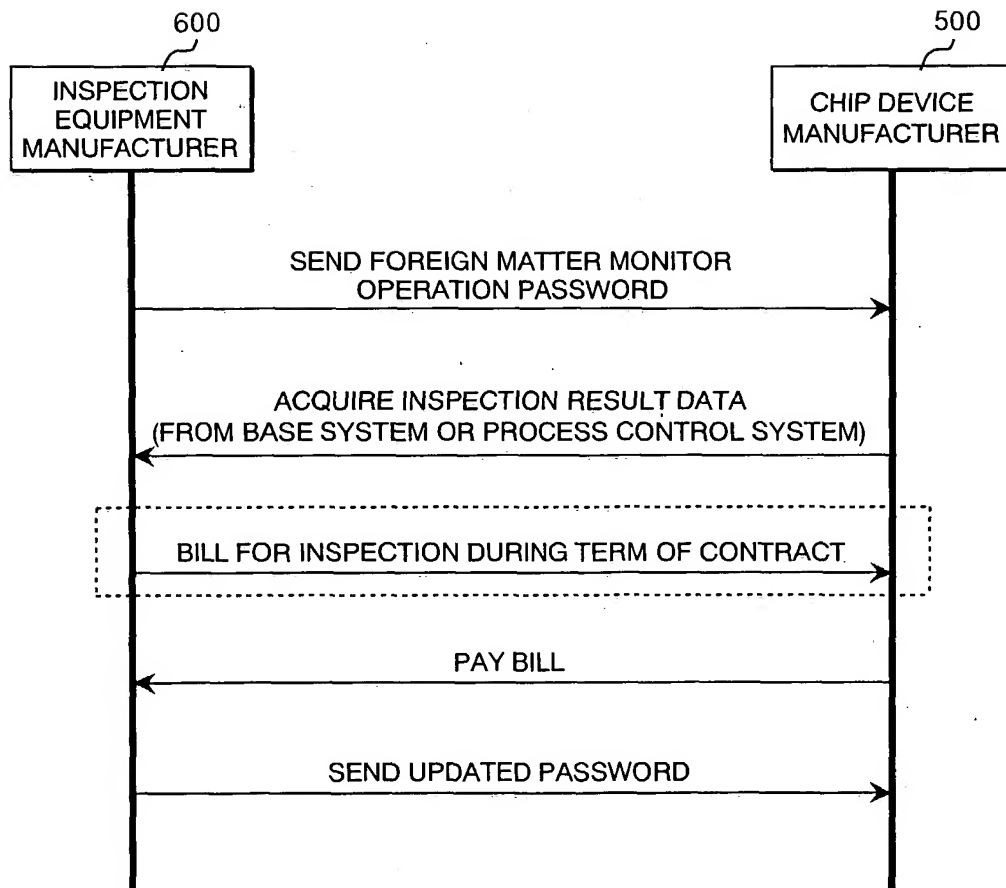
FIG. 33

FIG. 34

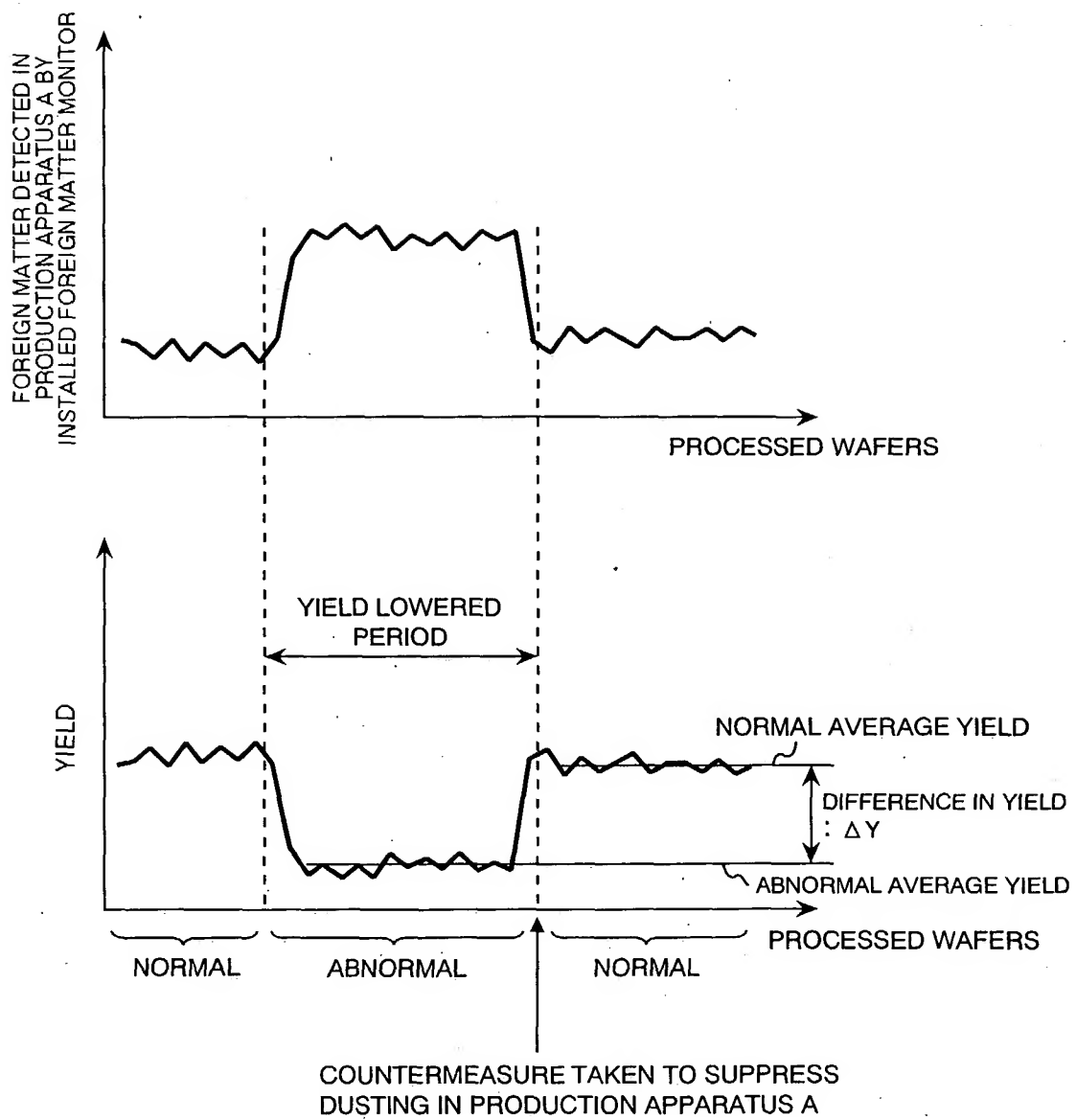


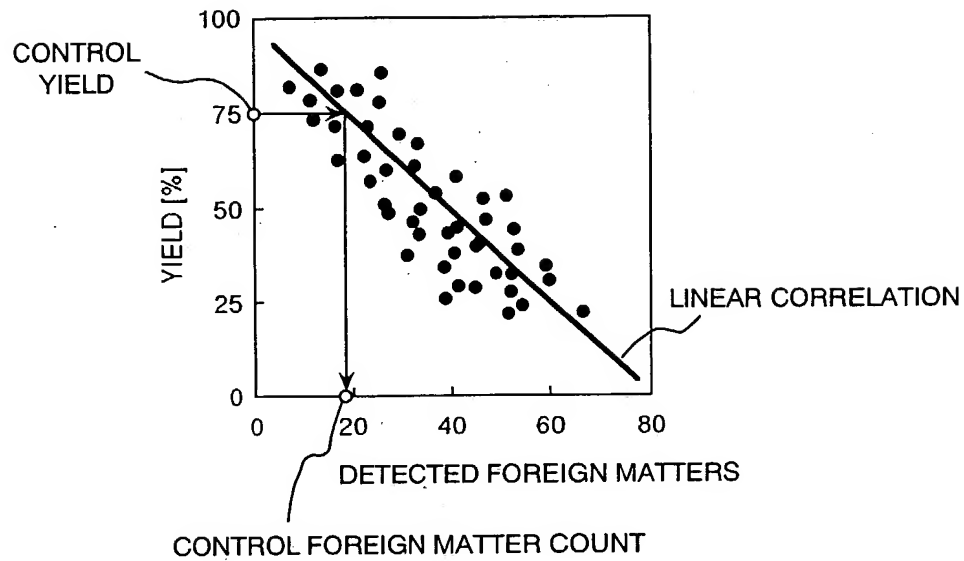
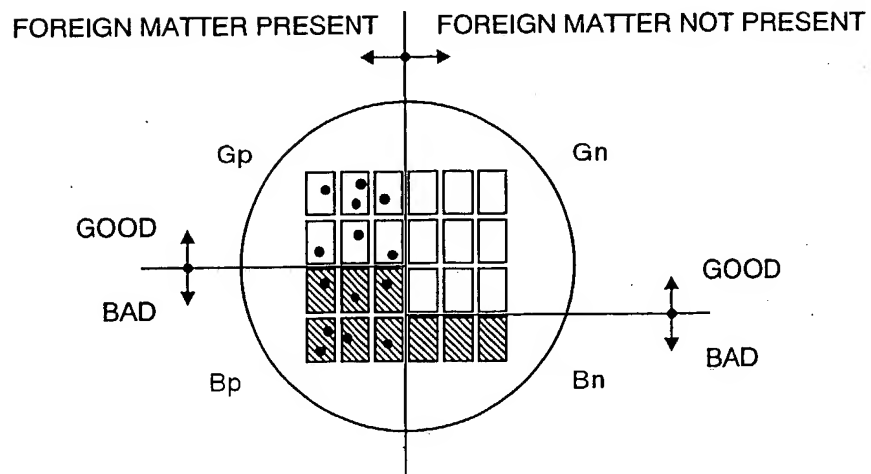
FIG. 35**FIG. 36**

FIG. 37

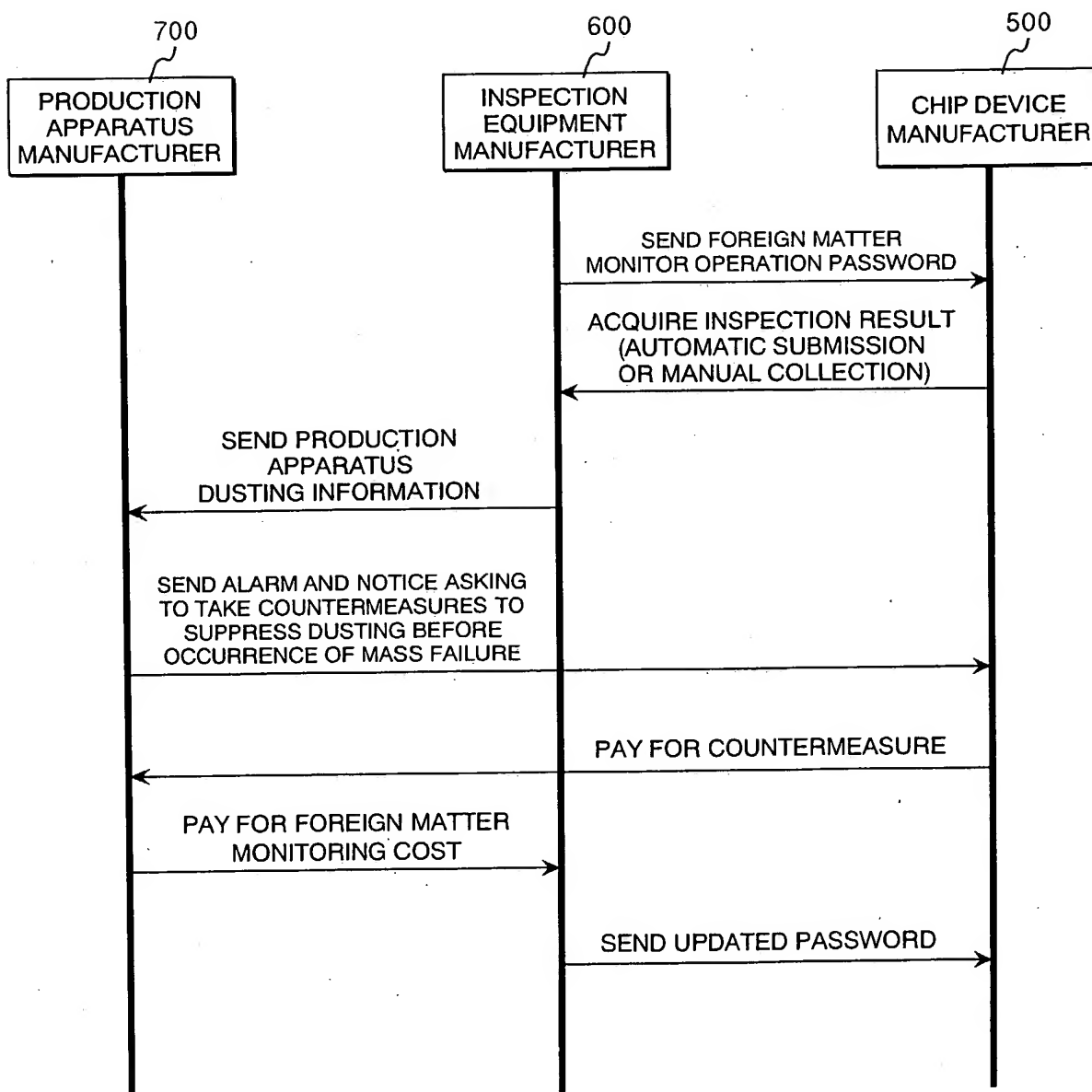


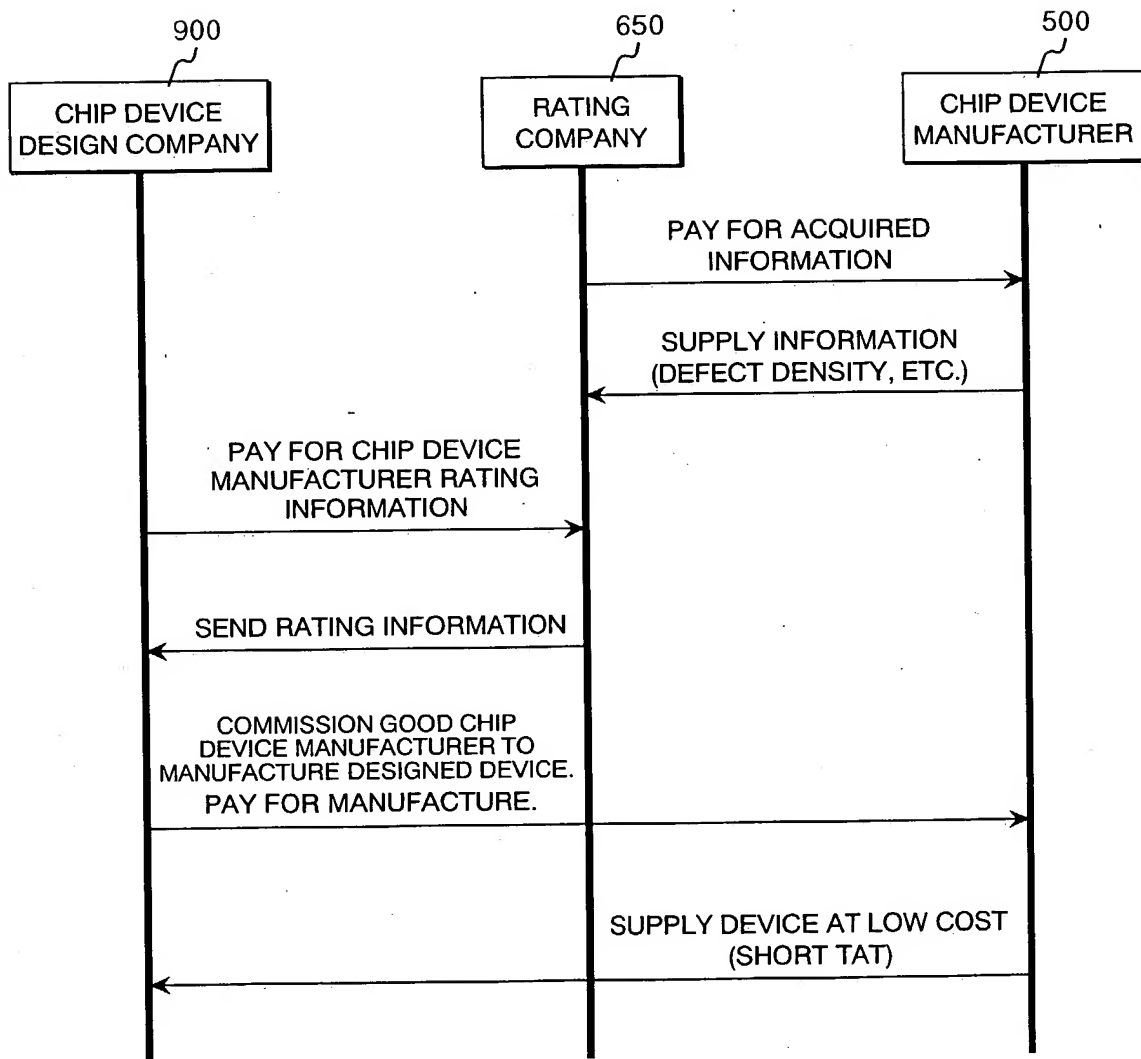
FIG. 38

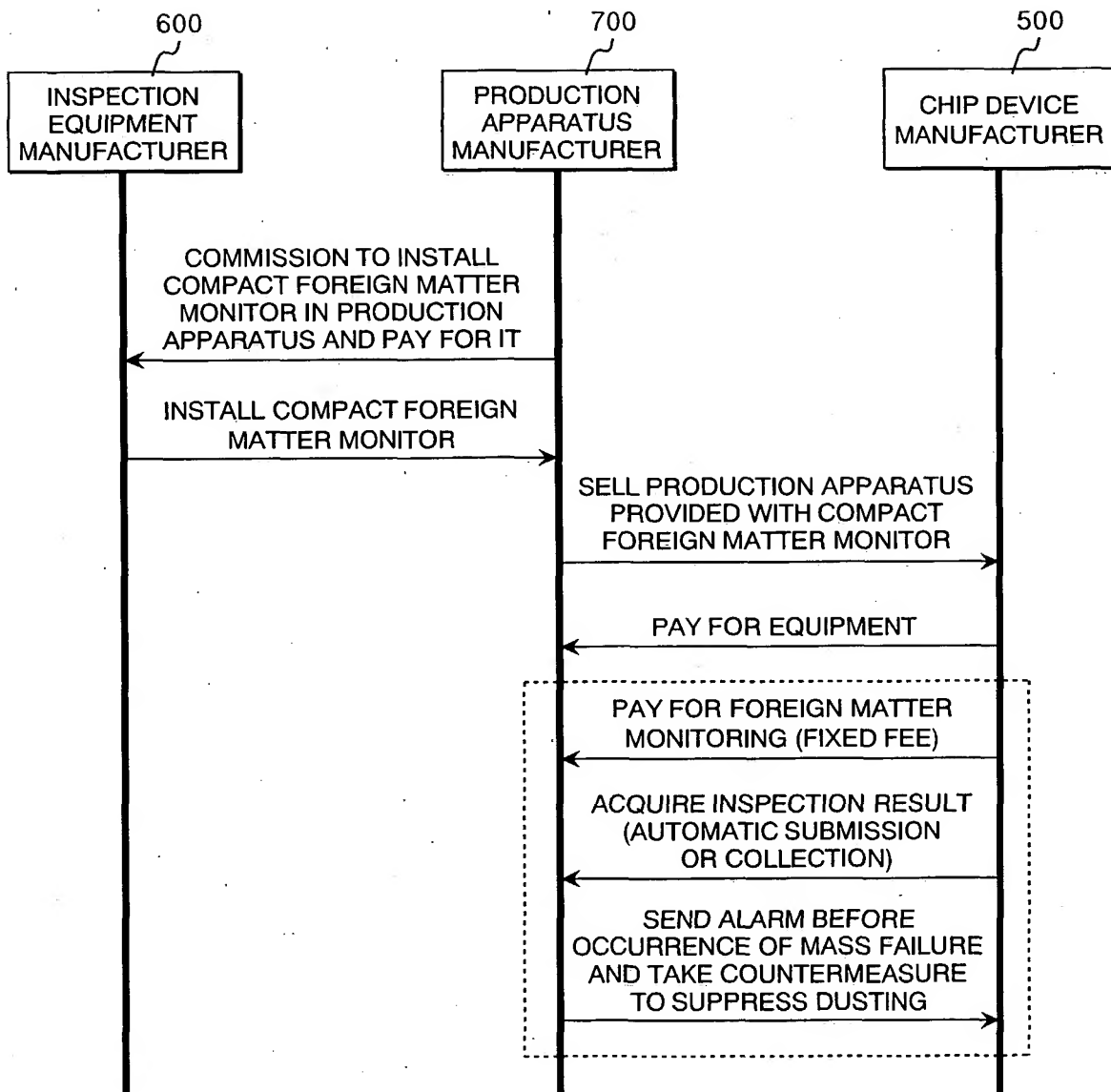
FIG. 39

FIG. 40